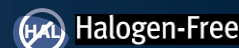


EPC2071 – Enhancement Mode Power Transistor

 V_{DS} , 100 V $R_{DS(on)}$, 2.2 mΩ max I_D , 64 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:**Maximum Ratings**

PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
I_D	Continuous ($T_A = 25^\circ\text{C}$)	64	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$)	350	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	

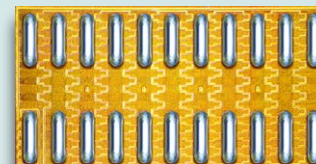
Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Case TOP)	0.4	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board (Case BOTTOM)	1.5	
$R_{\theta JA_JEDEC}$	Thermal Resistance, Junction-to-Ambient (using JEDEC 51-2 PCB)	59	
$R_{\theta JA_EVB}$	Thermal Resistance, Junction-to-Ambient (using EPC90122 EVB)	31	

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}, I_D = 0.15 \text{ mA}$	100			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 80 \text{ V}$		0.001	0.12	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.03	3.2	
	Gate-to-Source Forward Leakage [#]	$V_{GS} = 5 \text{ V}, T_J = 125^\circ\text{C}$		0.3	7.1	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.006	0.17	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 13 \text{ mA}$	0.7	1.3	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 30 \text{ A}$		1.7	2.2	mΩ
V_{SD}	Source-Drain Forward Voltage [#]	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.5		V

[#] Defined by design. Not subject to production test.



EPC2071 eGaN® FETs are supplied only in passivated die form with solder bars.
Die Size: 4.45 x 2.3 mm

Applications

- 48 V DC-DC Converters
- BLDC Motor Drives
- Sync Rectification for AC/DC and DC-DC
- Point of Load Converters
- Solar Converters
- Lidar
- eMobility

Benefits

- Ultra High Efficiency
- No Reverse Recovery
- Ultra Low Q_G, Q_{GD}, Q_{OSS}
- Ultra Low $R_{DS(on)}$
- Ultra Small Footprint



Dynamic Characteristics[#] ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		2664	3931	pF
C_{RSS}	Reverse Transfer Capacitance			5.4		
C_{OSS}	Output Capacitance			878	976	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 1)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		1058		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 2)			1422		
R_G	Gate Resistance			0.3		Ω
Q_G	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 30\text{ A}$		18	26	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 50\text{ V}, I_D = 30\text{ A}$		6.0		
Q_{GD}	Gate-to-Drain Charge			1.8		
$Q_{G(TH)}$	Gate Charge at Threshold			4.5		
Q_{OSS}	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		71	82	
Q_{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 1: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 2: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

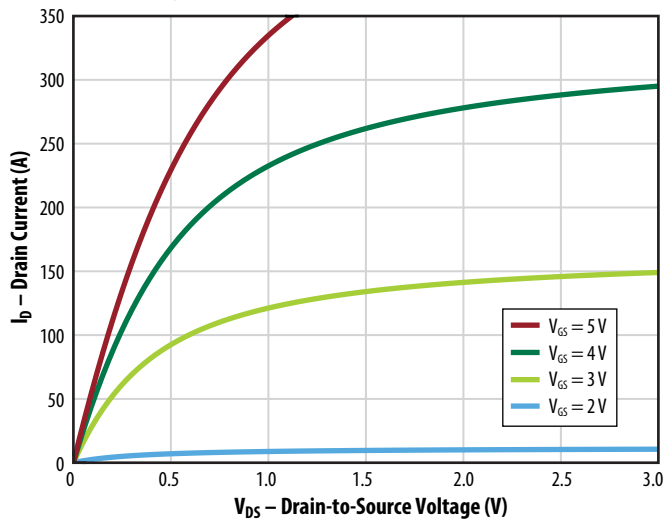
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Typical Transfer Characteristics

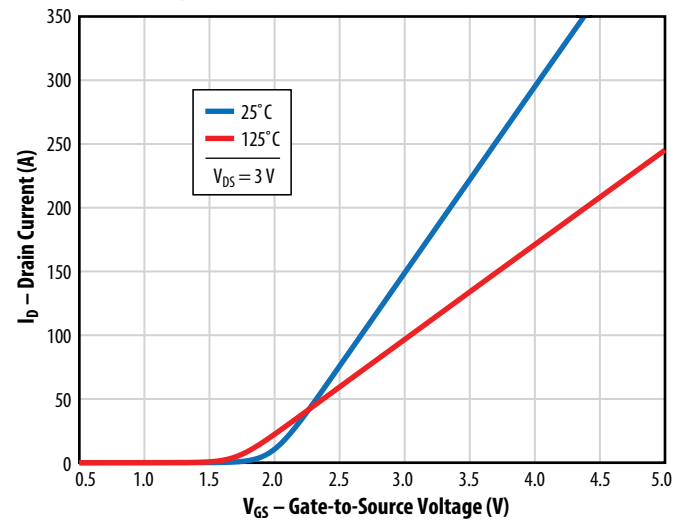
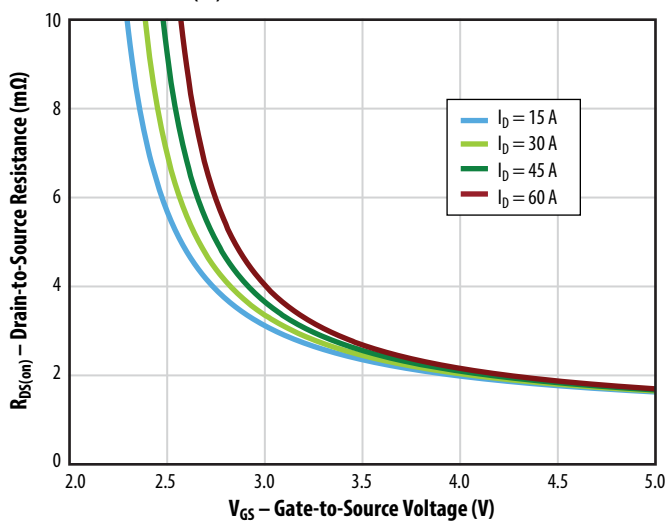
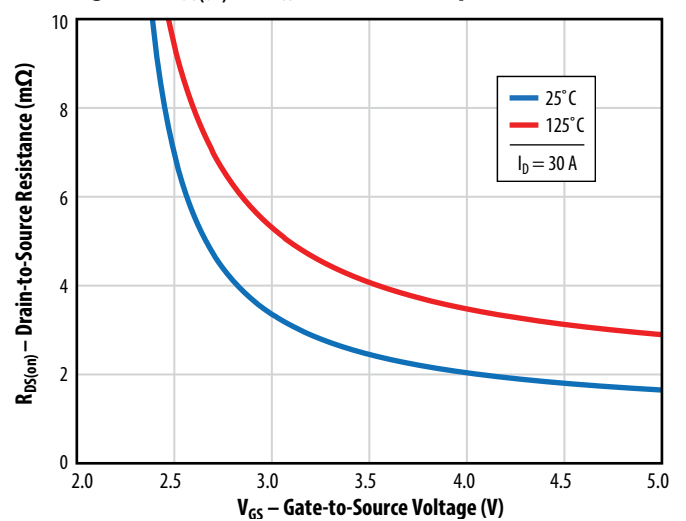
Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain CurrentsFigure 4: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Typical Capacitance (Linear Scale)

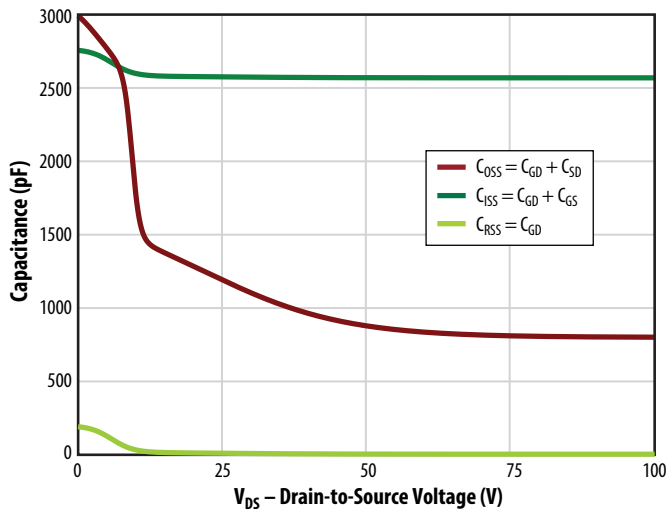


Figure 5b: Typical Capacitance (Log Scale)

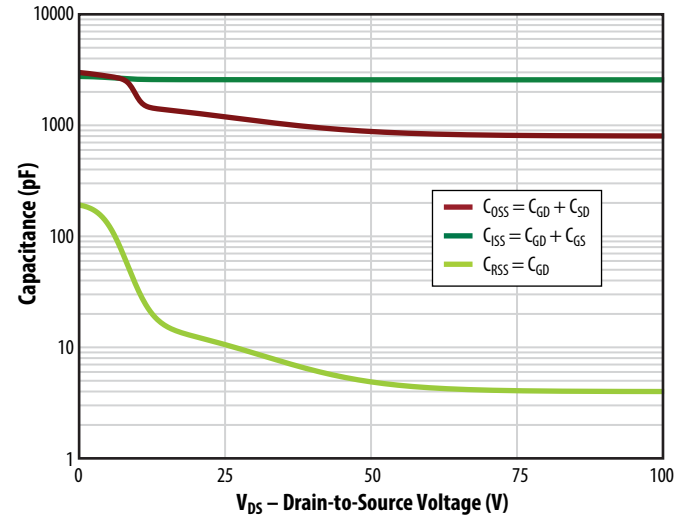
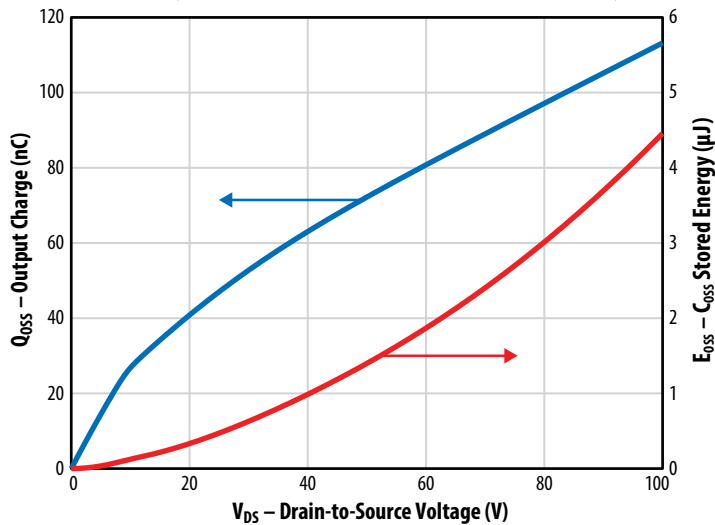
Figure 6: Typical Output Charge and C_{OSS} Stored Energy

Figure 7: Typical Gate Charge

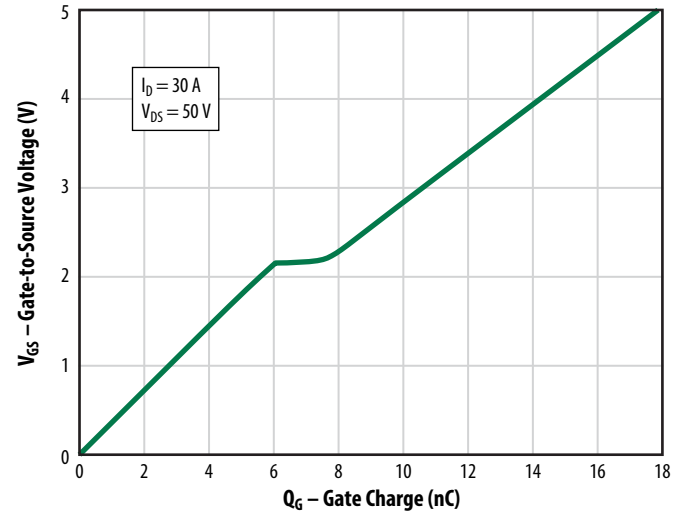


Figure 8: Reverse Drain-Source Characteristics

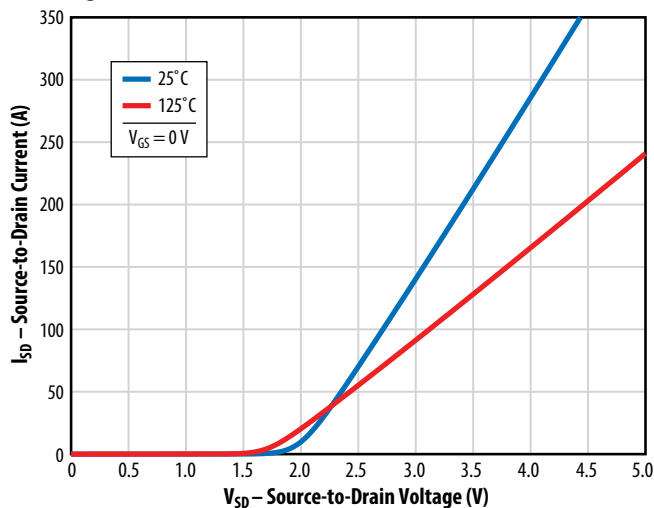
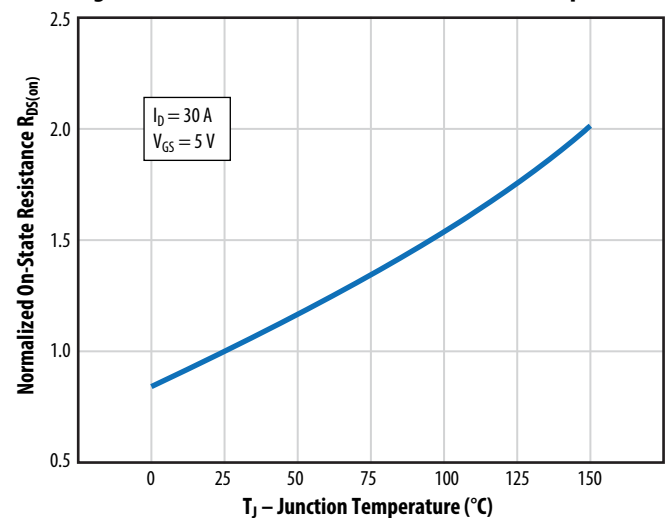


Figure 9: Normalized On-State Resistance vs. Temperature



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

Figure 10: Normalized Threshold Voltage vs. Temperature

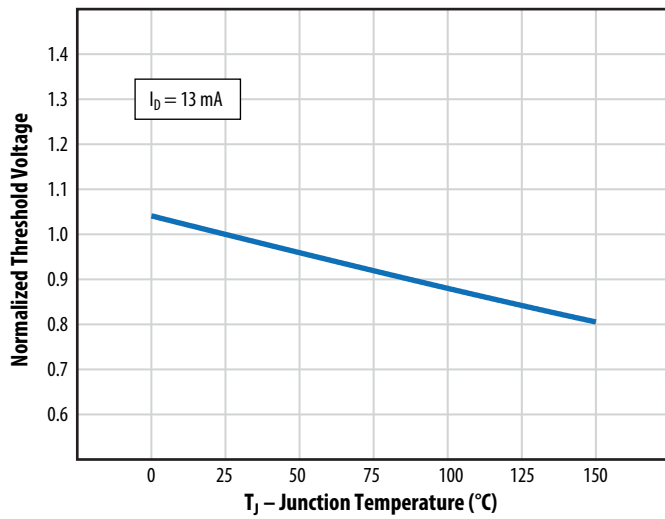


Figure 11: Safe Operating Area

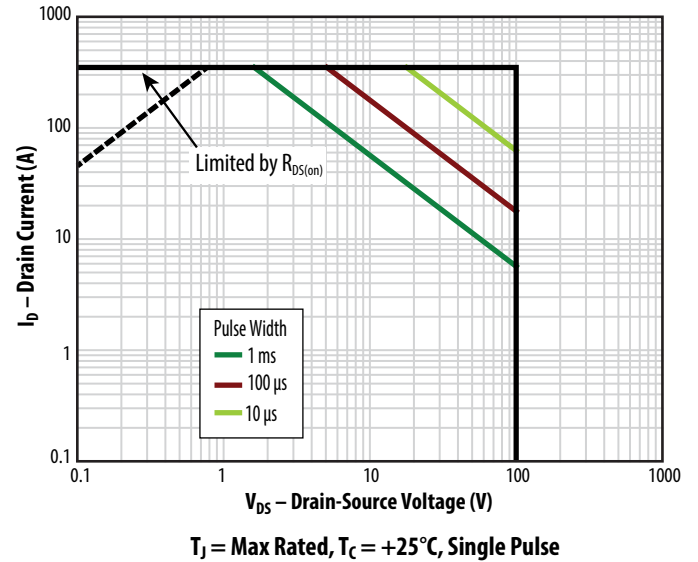
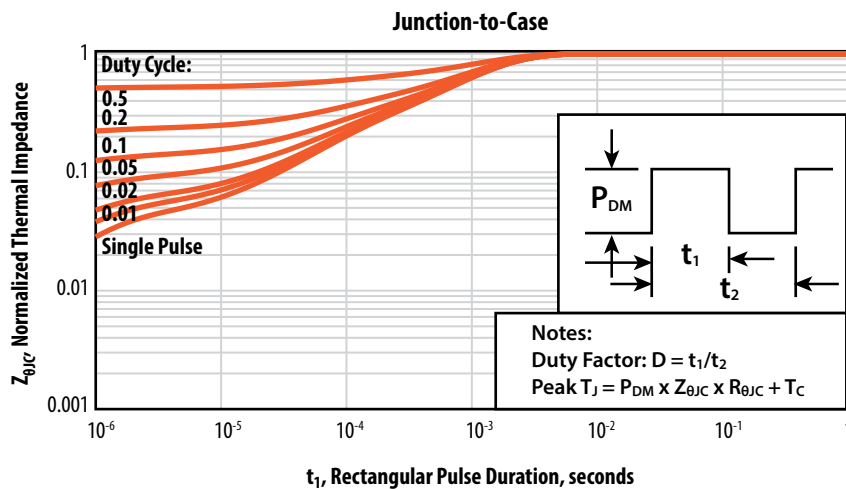
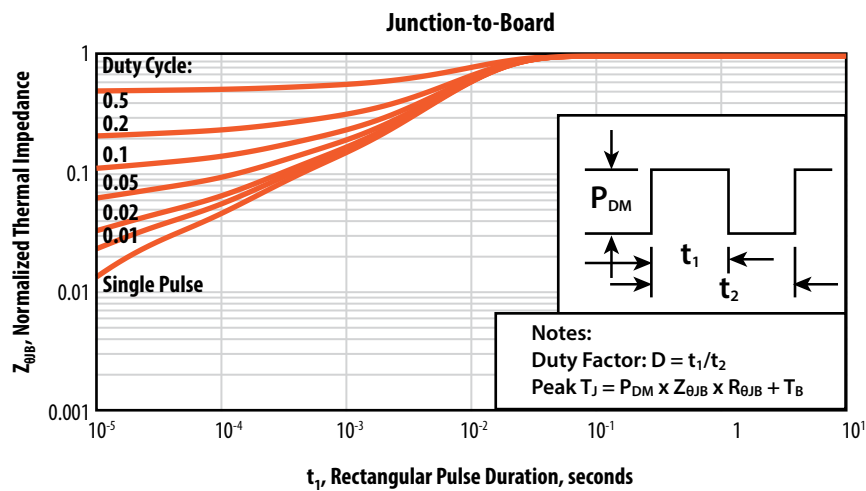


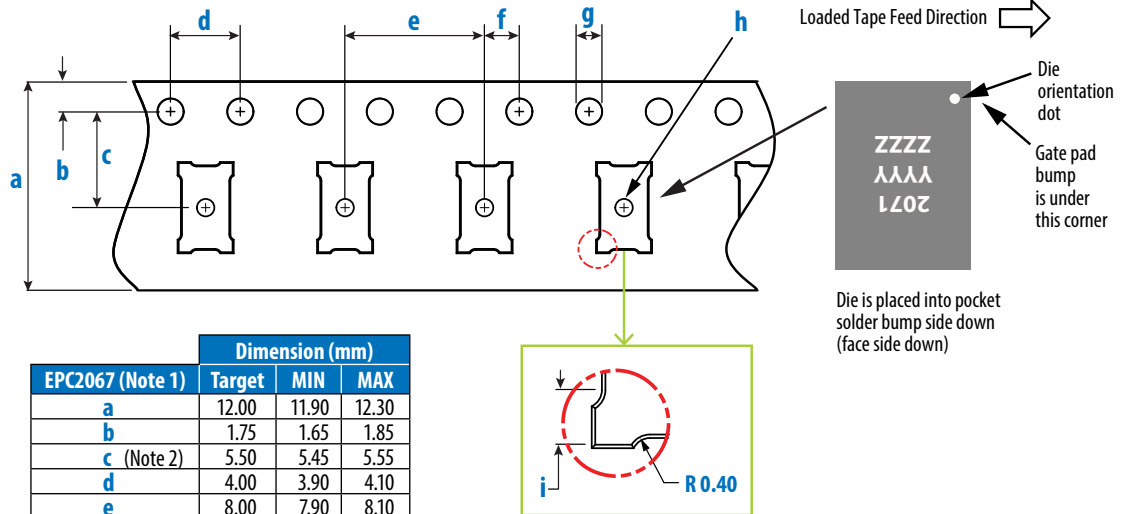
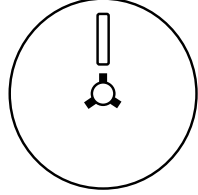
Figure 12: Transient Thermal Response Curves



TAPE AND REEL CONFIGURATION

8 mm pitch, 12 mm wide tape on 7" reel

7" inch reel

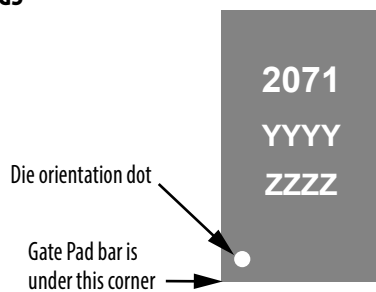


EPC2067 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.00	0.95	1.05
i	1.02		

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

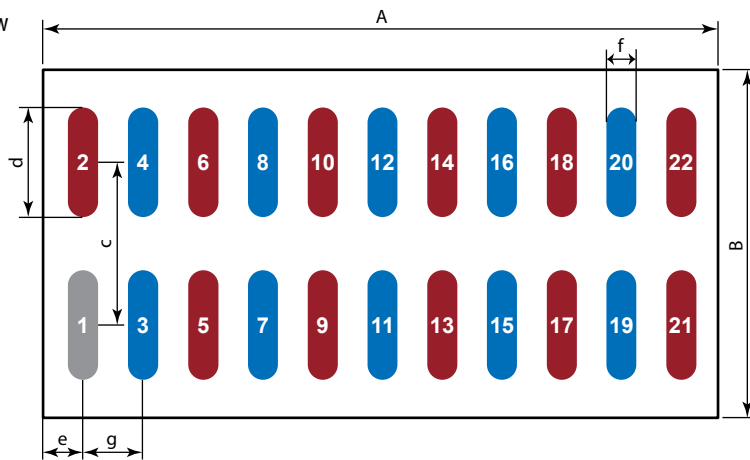
DIE MARKINGS



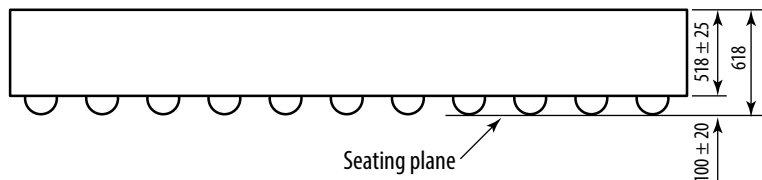
Part Number	Laser Markings		
	Part # Marking Line 1	Lot _Date Code Marking Line 2	Lot _Date Code Marking Line 3
EPC2071	2071	YYYY	ZZZZ

DIE OUTLINE

Solder Bump View



Side View



DIM	Micrometers		
	MIN	Nominal	MAX
A	4420	4450	4480
B	2270	2300	2330
c		1330	
d		720	
e		225	
f		200	
g		400	

Pad 1 is Gate;

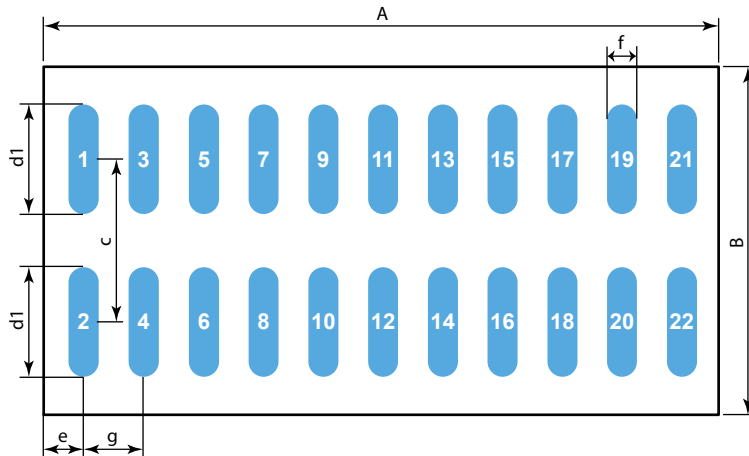
Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22 are Source;

Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20 are Drain;

*Substrate (top side) connected to Source

RECOMMENDED LAND PATTERN

(units in μm)



DIM	Micrometers
A	4450
B	2300
c	1330
d1	700
e	225
f	180
g	400

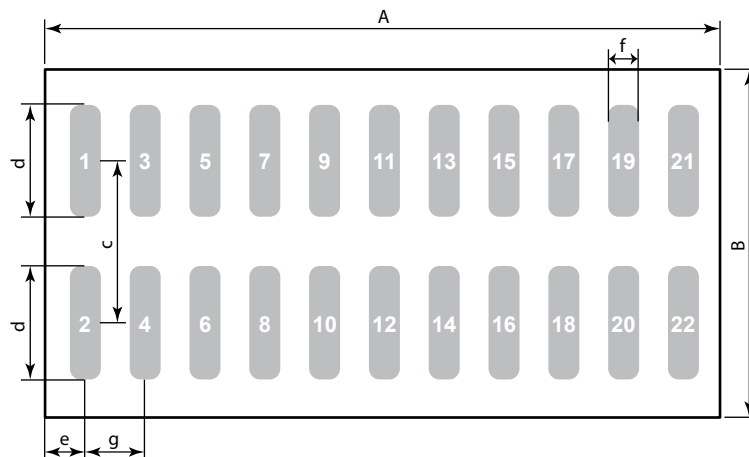
Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22 are Source;

Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20 are Drain

RECOMMENDED STENCIL DRAWING

(units in μm)



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

DIM	Micrometers
A	4450
B	2300
c	1330
d	700
e	225
f	180
g	400

Additional resources available:

- Assembly resources – https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf
- Library of Altium footprints for production FETs and ICs – <https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip> (for preliminary device Altium footprints, contact EPC)

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